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Docket No.: M4065.0361/P361 (PATENT)

### IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Letters Patent of:

Whonchee Lee, et al.

Patent No.: 6,867,448 B1

Issued: March 15, 2005

For: ELECTRO-MECHANICALLY POLISHED

STRUCTURE

Certificate

AUG 2 4 2005

of Correction

## REQUEST FOR CERTIFICATE OF CORRECTION PURSUANT TO 37 CFR 1.322 & 1.323

Commissioner for Patents

MS: Post Issue P.O. Box 1450

Alexandria, VA 22313-1450

Dear Sir:

Upon reviewing the above-identified patent, Patentees noted omissions and typographical errors which should be corrected.

### In the References Cited "U.S. Patent Documents":

The following U.S. Patents have been omitted and should be listed. They appear on the IDS we filed on February 6, 2004. The Examiner reviewed and acknowledged review of the references by initialing the IDS on May 20, 2004.

6,103,096

08/15/2000

Datta, et al.

6,280,581

08/28/2001

Cheng

08/19/2005 SSITHIB1 00000131 6867448

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U.S. Patent No.: 6,867,448 B1 Docket No.: M4065.0361/P361

6,379,223

04/30/2002

Sun, et al.

### In the References Cited "Other Publications":

The following reference has errors in the citation which should be corrected:

On page 2: Huang, C.S. et al., "A Novel UV Baking Process to Improve DUV Photoresist Hardness," pp. 135-138, Proceedings of Technical Papers: June 8-10, 1999, Taipei, Taiwan, Institute of Electrical and Electronics Engineers, Inc., September 1999. "pp. 135-138, Proceedings of" should read --pp. 135-138; Proceedings of the 1999 International Symposium on VLSI Technology, Systems and Applications: Proceedings of--.

### In the Specification:

Column. 1, line 24, "wells" should read --well--;

Column. 3, line 61, "alloy" should read --alloys--.

The grammatical errors in the specification, Col. 1, line 24 and Col. 3, line 61, were found in the application as-filed by the Patentees. The grammatical errors now sought to be corrected are inadvertent typographical errors, the correction of which does not involve new matter or require reexamination. Please charge our Credit Card in the amount of \$100.00 covering the fee set forth in 37 CFR 1.20(a). Credit Card Payment Form SB-2038, with a signature from an authorized cardholder, is enclosed.

The omissions and typographical errors in the References Cited portions were <u>not</u> in the application as-filed or amended by the Patentees. The errors sought to be corrected are inadvertent omissions and typographical errors on the part of the USPTO, the correction of which does not involve new matter or require reexamination.

U.S. Patent No.: 6,867,448 B1 Docket No.: M4065.0361/P361

Transmitted herewith is a proposed Certificate of Correction effecting such amendment. Patentees respectfully solicit the granting of the requested Certificate of Correction.

The Commissioner is also hereby authorized to charge any deficiency in the fees filed, asserted to be filed or which should have been filed herewith (or with any paper hereafter filed in this application by this firm) to our Deposit Account No. 04-1073, under Order No. M4065.0361/P361. A duplicate copy of this paper is enclosed.

Dated: August 18, 2005

Respectfully submitted,

Thomas J. D'Amico

Registration No.: 28,371

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PTO/SB/17 (12-04v2)
Approved for use through 7/31/2006. OMB 0651-0032
U.S. Patent and Trademark Office; U.S. DEPARTMENT OF COMMERCE duction Act of 1995, no person are required to respond to a collection of information unless it displays a valid OMB control number. Complete if Known Effective on 12/08/2004. Fees pursuant to the Consolidated Appropriations Act, 2005 (H.R. 4818). Application Number Patent#: 6,867,448 Issued: March 15, 2005 TRANSMITTAL Filing Date Whonchee Lee First Named Inventor For FY 2005 **Examiner Name** J. H. Nguyen Applicant claims small entity status. See 37 CFR 1.27 2815 Art Unit M4065.0361/P361 Attorney Docket No. TOTAL AMOUNT OF PAYMENT 100.00 METHOD OF PAYMENT (check all that apply) x Credit Card Money Order None Other (please identify): Check Dickstein Shapiro Morin & Oshinsky LLP Deposit Account Number: 04-1073 Deposit Account Name: For the above-identified deposit account, the Director is hereby authorized to: (check all that apply) Charge fee(s) indicated below, except for the filing fee Charge fee(s) indicated below Charge any additional fee(s) or underpayment of fee(s) under 37 CFR 1.16 and 1.17 x Credit any overpayments **FEE CALCULATION** 1. BASIC FILING, SEARCH, AND EXAMINATION FEES **EXAMINATION FEES FILING FEES** SEARCH FEES Smail Entity **Small Entity** Small Entity Fees Paid (\$) Fee (\$) Fee (\$) Fee (\$) Fee (\$) Fee (\$) Fee (\$) **Application Type** 200 100 250 500 300 150 Utility 50 130 65 200 100 100 Design 200 100 300 150 160 80 Plant 500 250 600 300 150 300 Reissue 0 200 100 **Provisional** Small Entity 2. EXCESS CLAIM FEES Fee (\$) Fee (\$) Fee Description 25 50 Each claim over 20 (including Reissues) 100 200 Each independent claim over 3 (including Reissues) 180 360 Multiple dependent claims Multiple Dependent Claims Fee Paid (\$) **Total Claims Extra Claims** Fee (\$) Fee Paid (\$) Fee Paid (\$) Extra Claims Indep. Claims Fee (\$) 3. APPLICATION SIZE FEE If the specification and drawings exceed 100 sheets of paper (excluding electronically filed sequence or computer listings under 37 CFR 1.52(e)), the application size fee due is \$250 (\$125 for small entity) for each additional 50 sheets or fraction thereof. See 35 U.S.C. 41(a)(1)(G) and 37 CFR 1.16(s). Number of each additional 50 or fraction thereof Fee Paid (\$) Fee (\$) **Total Sheets Extra Sheets** (round up to a whole number) x - 100 = Fees Paid (\$) 4. OTHER FEE(S) Non-English Specification, \$130 fee (no small entity discount) 100.00 Other (e.g., late filing surcharge): 1811 Certificate of correction SUBMITTED BY Registration No. (Attorney/Agent) Telephone (202) 828-2232 28,371 Signature Date August 18, 2005 Name (Print/Type) Thomas J. D'Amico

# UNITED STATES PATENT AND TRADEMARK OFFICE CERTIFICATE OF CORRECTION

PATENT NO.

6,867,448 B1

Page 1 of 1

DATED

March 15, 2005

**INVENTORS** 

Whonchee Lee, et al.

It is certified that omissions and typographical errors appear in the above-identified patent and that said Letters Patent is hereby corrected by the information shown below:

#### In the References Cited "U.S. Patent Documents":

The following U.S. Patents have been omitted and should be added:

6,103,096

08/15/2000

Datta, et al.

6,280,581

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### MAILING ADDRESS OF SENDER:

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Washington, DC 20037-1526

PATENT NO. 6,867,448 B1